

Radiation Hardened, 5.0V/3.3V μ -Processor Supervisory Circuits

**ISL705AEH, ISL705BEH, ISL705CEH, ISL706AEH, ISL706BEH, ISL706CEH
ISL705ARH, ISL705BRH, ISL705CRH, ISL706ARH, ISL706BRH,
ISL706CRH**

This family of devices are radiation hardened 5.0V/3.3V supervisory circuits that reduce the complexity required to monitor supply voltages in microprocessor systems. These devices significantly improve accuracy and reliability relative to discrete solutions. Each IC provides four key functions.

1. A reset output during power-up, power-down and brownout conditions.
2. An independent watchdog output that goes low if the watchdog input has not been toggled within 1.6s.
3. A precision threshold detector for monitoring a power supply other than V_{DD} .
4. An active-low manual-reset input.

Applications

- Supervisor for μ -processors, μ -controllers, FPGAs and DSPs
- Critical power supply monitoring
- Reliable replacement of discrete solutions

Related Literature

- [AN1650](#) "ISL705xRH Evaluation Board User's Guide"
- [AN1671](#) "ISL706xRH Evaluation Board User Guide"
- [AN1651](#) "Single Event Effects (SEE) Testing of the ISL705xRH/EH and ISL706xRH/EH Rad Hard Supervisory Circuits"
- ["Total Dose Testing of the ISL706ARH Radiation Hardened Microprocessor Supervisory Circuit"](#)
- [AN1710](#) "ISL705xRH and IS706xRH SPICE Model"

Features

- Electrically screened to SMD [5962-11213](#)
- QML qualified per MIL-PRF-38535 requirements
- Radiation hardness
 - High dose rate (EH and RH) 100krad(Si)
 - Low dose rate (EH only) 100krad(Si) (*)
 - SEL/SEB LET_{TH} 86MeV/mg/cm²

*Product capability established by initial characterization. The EH version is acceptance tested on a wafer-by-wafer basis to 50krad(Si) at low dose rate.

- Precision supply voltage monitor
 - 4.65V threshold in the ISL705AxH/BxH/CxH
 - 3.08V threshold in the ISL706AxH/BxH/CxH
- 200ms (typical) reset pulse width
 - Active high, active low and open drain options
- Independent watchdog timer with 1.6s (typical) timeout
- Precision threshold detector
 - 1.25V threshold in the ISL705AxH/BxH/CxH
 - 0.6V threshold in the ISL706AxH/BxH/CxH
- Debounced TTL/CMOS compatible manual-reset input
- Reset output valid at $V_{DD} = 1.2V$

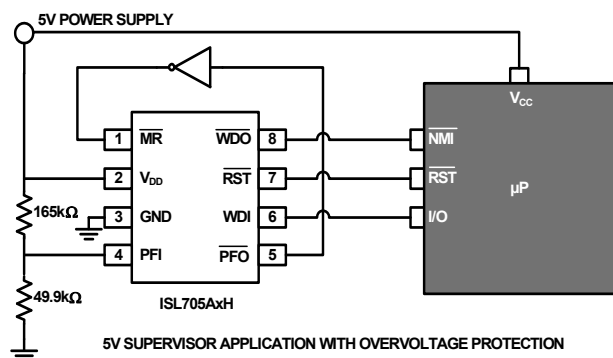


FIGURE 1. TYPICAL APPLICATION

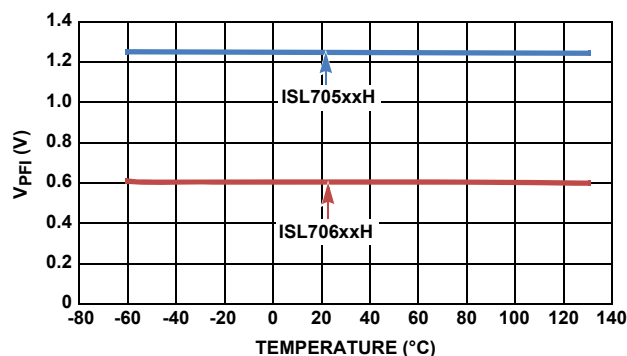


FIGURE 2. PRECISION THRESHOLD DETECTOR TEMPERATURE CHARACTERISTICS CURVE

Ordering Information

ORDERING SMD NUMBER (Note 1)	PART NUMBER (Note 2)	TEMP RANGE (°C)	PACKAGE (RoHS COMPLIANT)	PKG. DWG. #
5962R1121307VXC	ISL705AEHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121307V9A	ISL705AEHVX	-55 to +125	Die	
N/A	ISL705ARHF/PROTO	-55 to +125	8 Ld Flatpack	K8.A
N/A	ISL705ARHX/SAMPLE	-55 to +125	Die	
5962R1121301QXC	ISL705ARHQF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121301VXC	ISL705ARHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121301V9A	ISL705ARHVX	-55 to +125	Die	
5962R1121308VXC	ISL705BEHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121308V9A	ISL705BEHVX	-55 to +125	Die	
N/A	ISL705BRHF/PROTO	-55 to +125	8 Ld Flatpack	K8.A
N/A	ISL705BRHX/SAMPLE	-55 to +125	Die	
5962R1121302QXC	ISL705BRHQF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121302VXC	ISL705BRHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121302V9A	ISL705BRHVX	-55 to +125	Die	
5962R1121309VXC	ISL705CEHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121309V9A	ISL705CEHVX	-55 to +125	Die	
N/A	ISL705CRHF/PROTO	-55 to +125	8 Ld Flatpack	K8.A
N/A	ISL705CRHX/SAMPLE	-55 to +125	Die	
5962R1121303QXC	ISL705CRHQF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121303VXC	ISL705CRHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121303V9A	ISL705CRHVX	-55 to +125	Die	
5962R1121310VXC	ISL706AEHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121310V9A	ISL706AEHVX	-55 to +125	Die	
N/A	ISL706ARHF/PROTO	-55 to +125	8 Ld Flatpack	K8.A
N/A	ISL706ARHX/SAMPLE	-55 to +125	Die	
5962R1121304QXC	ISL706ARHQF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121304VXC	ISL706ARHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121304V9A	ISL706ARHVX	-55 to +125	Die	
5962R1121311VXC	ISL706BEHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121311V9A	ISL706BEHVX	-55 to +125	Die	
N/A	ISL706BRHF/PROTO	-55 to +125	8 Ld Flatpack	K8.A
N/A	ISL706BRHX/SAMPLE	-55 to +125	Die	
5962R1121305QXC	ISL706BRHQF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121305VXC	ISL706BRHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121305V9A	ISL706BRHVX	-55 to +125	Die	
5962R1121312VXC	ISL706CEHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121312V9A	ISL706CEHVX	-55 to +125	Die	
N/A	ISL706CRHF/PROTO	-55 to +125	8 Ld Flatpack	K8.A
N/A	ISL706CRHX/SAMPLE	-55 to +125	Die	

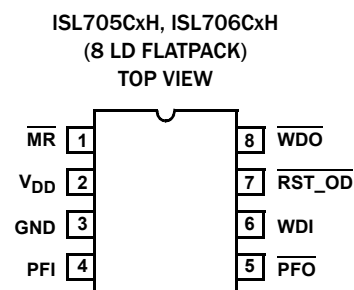
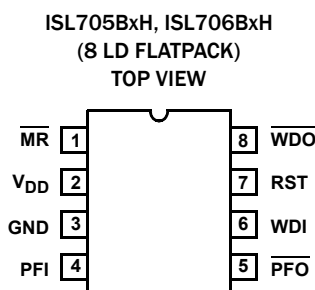
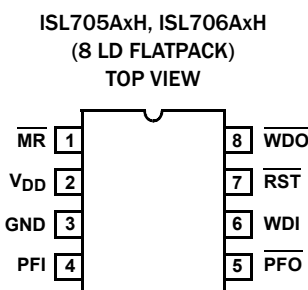
Ordering Information (Continued)

ORDERING SMD NUMBER (Note 1)	PART NUMBER (Note 2)	TEMP RANGE (°C)	PACKAGE (RoHS COMPLIANT)	PKG. DWG. #
5962R1121306QXC	ISL706CRHQF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121306VXC	ISL706CRHVF	-55 to +125	8 Ld Flatpack	K8.A
5962R1121306V9A	ISL706CRHVX	-55 to +125	Die	
N/A	ISL705XRHEVAL1Z	ISL705XRH Evaluation Board		
N/A	ISL706XRHEVAL1Z	ISL706XRH Evaluation Board		

NOTE:

- Specifications for Rad Hard QML devices are controlled by the Defense Logistics Agency Land and Maritime (DLA). The SMD numbers listed must be used when ordering.
- These Intersil Pb-free Hermetic packaged products employ 100% Au plate - e4 termination finish, which is RoHS compliant and compatible with both SnPb and Pb-free soldering operations.

Pin Configurations



Pin Descriptions

ISL705AxH ISL706AxH	ISL705BxH ISL706BxH	ISL705CxH ISL706CxH	PIN NAME	DESCRIPTION
1	1	1	$\overline{\text{MR}}$	Manual Reset. $\overline{\text{MR}}$ is an active-low, debounced, TTL/CMOS compatible input that may be used to trigger a reset pulse.
2	2	2	V_{DD}	Power Supply. V_{DD} is a supply voltage input that provides power to all internal circuitry. This input is also monitored and used to trigger a reset pulse. Reset is guaranteed operable after V_{DD} rises above 1.2V.
3	3	3	GND	Ground. GND is a supply voltage return for all internal circuitry. This return establishes the reference level for voltage detection and should be connected to signal ground.
4	4	4	PFI	Power Fall Input. PFI is an input to a threshold detector, which may be used to monitor another supply voltage level. The threshold of the detector (V_{PFI}) is 1.25V in the ISL705AxH/BxH/CxH and 0.6V in the ISL706AxH/BxH/CxH.
5	5	5	$\overline{\text{PFO}}$	Power Fall Output. $\overline{\text{PFO}}$ is an active-low, push-pull output of a threshold detector that indicates the voltage at the PFI pin is less than V_{PFI} .
6	6	6	WDI	Watchdog Input. WDI is a tri-state input that monitors microprocessor activity. If the microprocessor does not toggle WDI within 1.6s and WDI is not tri-stated, $\overline{\text{WDO}}$ goes low. As long as reset is asserted or WDI is tri-stated, the watchdog timer will stay cleared and will not count. As soon as reset is released and WDI is driven high or low, the timer will start counting. Floating WDI or connecting WDI to a high impedance tri-state buffer disables the watchdog feature.

Pin Descriptions (Continued)

ISL705AxH ISL706AxH	ISL705BxH ISL706BxH	ISL705CxH ISL706CxH	PIN NAME	DESCRIPTION
7	-	-	$\overline{\text{RST}}$	Reset. $\overline{\text{RST}}$ is an active-low, push-pull output that is guaranteed to be low once V_{DD} reaches 1.2V. As V_{DD} rises, $\overline{\text{RST}}$ stays low. When V_{DD} rises above a 4.65V (ISL705AxH/BxH/CxH) or 3.08V (ISL706AxH/BxH/CxH) reset threshold, an internal timer releases $\overline{\text{RST}}$ after about 200ms. $\overline{\text{RST}}$ pulses low whenever V_{DD} goes below the reset threshold. If a brownout condition occurs in the middle of a previously initiated reset pulse, the pulse will continue for at least 140ms. On power-down, once V_{DD} falls below the reset threshold, $\overline{\text{RST}}$ goes low and is guaranteed low until V_{DD} drops below 1.2V.
-	7	-	RST	Reset. RST is an active-high, push-pull output. RST is the inverse of $\overline{\text{RST}}$.
-	-	7	$\overline{\text{RST_OD}}$	Reset. $\overline{\text{RST_OD}}$ is an active-low, open-drain output that goes low when reset is asserted. This pin may be pulled up to V_{DD} with a resistor consistent with the sink and leakage current specifications of the output. Behavior is otherwise identical to the $\overline{\text{RST}}$ pin.
8	8	8	$\overline{\text{WDO}}$	Watchdog Output. $\overline{\text{WDO}}$ is an active-low, push-pull output that goes low if the microprocessor does not toggle WDI within 1.6s and WDI is not tri-stated. $\overline{\text{WDO}}$ is usually connected to the non-maskable interrupt input of a microprocessor. When V_{DD} drops below the reset threshold, $\overline{\text{WDO}}$ will go low whether or not the watchdog timer has timed out. Reset is simultaneously asserted, thus preventing an interrupt. Since floating WDI disables the internal timer, $\overline{\text{WDO}}$ goes low only when V_{DD} drops below the reset threshold, thus functioning as a low line output.

Functional Block Diagrams

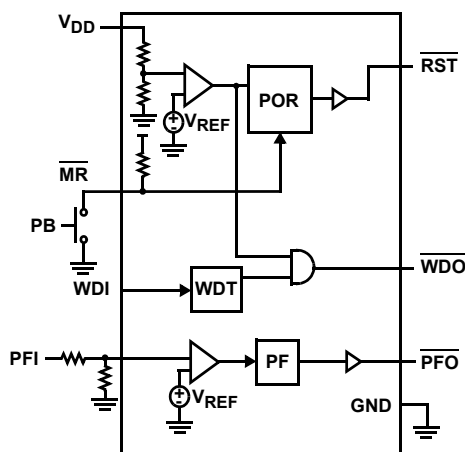


FIGURE 3A. ISL705AxH, ISL706AxH

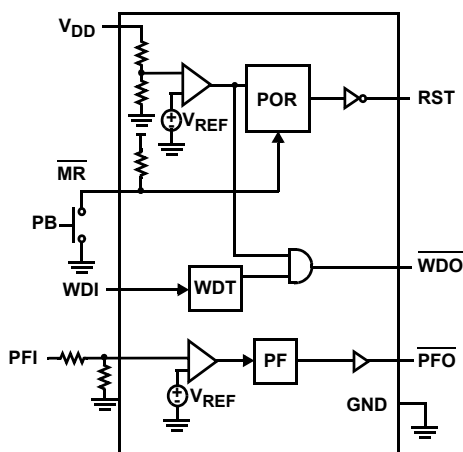


FIGURE 3B. ISL705BxH, ISL706BxH

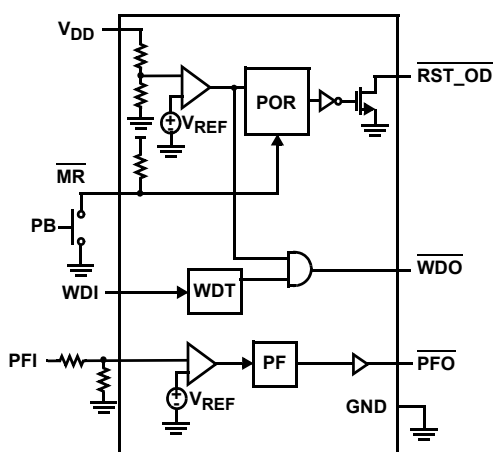


FIGURE 3C. ISL705CxH, ISL706CxH

FIGURE 3. FUNCTIONAL BLOCK DIAGRAMS

Timing Diagrams

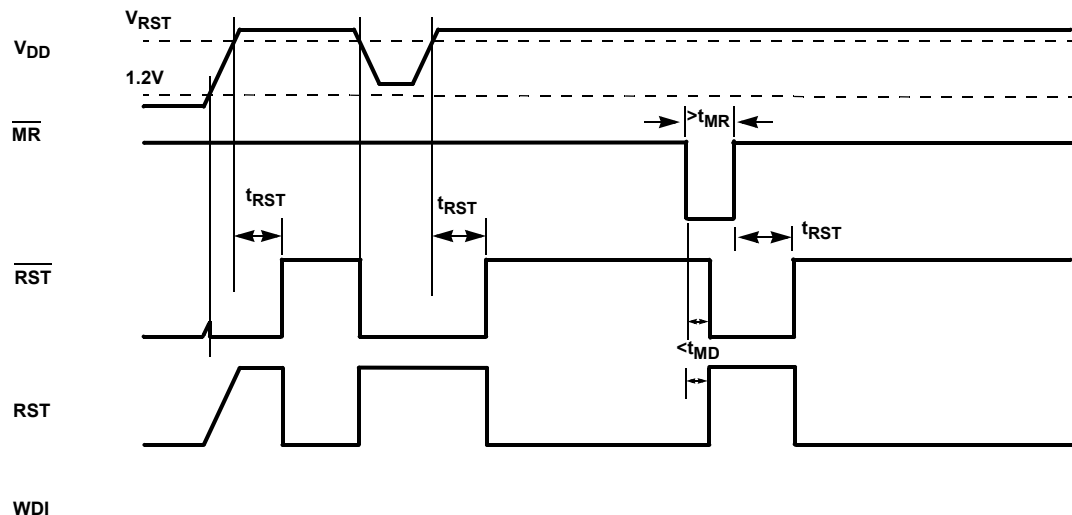


FIGURE 4. RST, $\overline{\text{RST}}$, $\overline{\text{MR}}$ TIMING DIAGRAM

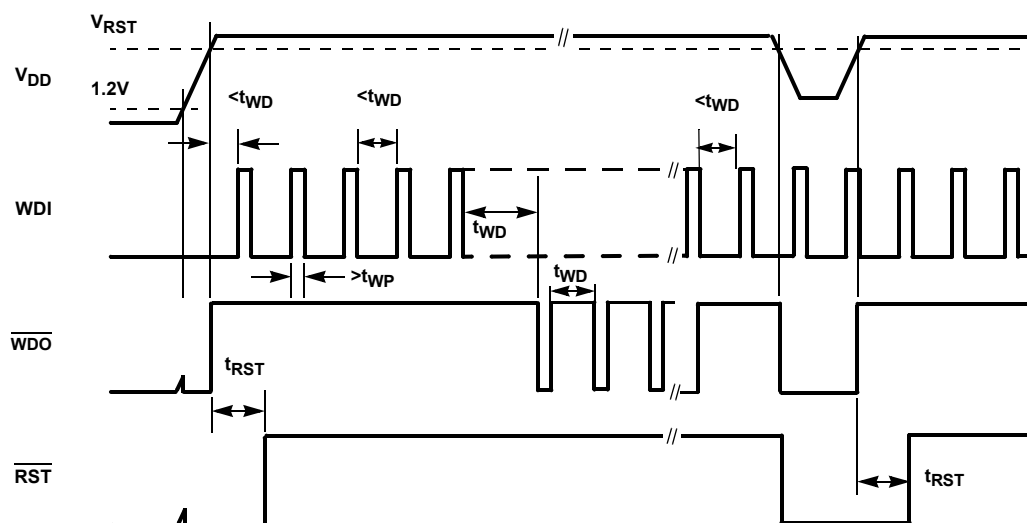


FIGURE 5. WATCHDOG TIMING DIAGRAM

Absolute Maximum Ratings

Supply Voltage Range	-0.3V to 6.5V
Voltage on All Other Inputs	-0.3V to $V_{DD} + 0.3V$
ESD Rating	
Human Body Model (Tested per MIL-PRF-883 3015.7)	3.0kV
Machine Model (Tested per JESD22-A115C)	300V
Charged Device Model (Tested per JESD22-C110D)	1.0kV
Latch-Up (Tested per JESD-78C)	Class 2, Level A

Thermal Information

Thermal Resistance (Typical)	θ_{JA} (°C/W)	θ_{JC} (°C/W)
8 Ld Flatpack Package (Notes 3, 4)	140	15
Maximum Junction Temperature	+175°C	
Storage Temperature Range	-65°C to +150°C	

Recommended Operating Conditions

Temperature	-55°C to +125°C
Supply Voltage	
ISL705AxH/BxH/CxH	4.75V to 5.5V
ISL706AxH/BxH/CxH	3.15V to 3.6V

CAUTION: Do not operate at or near the maximum ratings listed for extended periods of time. Exposure to such conditions may adversely impact product reliability and result in failures not covered by warranty.

NOTES:

- θ_{JA} is measured with the component mounted on a low effective thermal conductivity test board in free air. See Tech Brief [TB379](#) for details.
- For θ_{JC} , the “case temp” location is the center of the package underside.

Electrical Specifications Unless otherwise specified $V_{DD} = 4.75V$ to $5.5V$ for the ISL705AxH/BxH/CxH, $V_{DD} = 3.15V$ to $3.6V$ for the ISL706AxH/BxH/CxH, $T_A = -55^\circ C$ to $+125^\circ C$. **Boldface limits apply across the operating temperature range, $-55^\circ C$ to $+125^\circ C$; over a total ionizing dose of 100krad(Si) with exposure at a high dose rate of 50 - 300krad(Si)/s; and over a total ionizing dose of 50krad(Si) with exposure at a low dose rate of <10mrads(Si)/s.**

PARAMETER	SYMBOL	TEST CONDITIONS	MIN (Note 5)	TYP (Note 6)	MAX (Note 5)	UNIT
POWER SUPPLY SECTION						
Operating Supply Voltage (Note 7)	V _{DD}	ISL705AxH/BxH/CxH	1.2	5	5.5	V
		ISL706AxH/BxH/CxH	1.2	3.3	3.6	V
Operating Supply Current	I _{DD}	ISL705AxH/BxH/CxH			530	μA
		ISL706AxH/BxH/CxH			400	μA
RESET SECTION						
Reset Threshold Voltage	V _{RST}	ISL705AxH/BxH/CxH	4.50	4.65	4.75	V
		ISL706AxH/BxH/CxH	3.00	3.08	3.15	V
Reset Threshold Voltage Hysteresis	V _{HYS}	ISL705AxH/BxH/CxH	20	40		mV
		ISL706AxH/BxH/CxH	20	30		mV
Reset Pulse Width	t _{RST}		140	200	280	ms
Reset Output Voltage	V _{OUT}	ISL705AxH/BxH, I _{SOURCE} = 800μA	V _{DD} - 1.5			V
		ISL705AxH/BxH/CxH, I _{SINK} = 3.2mA			0.4	V
		ISL706AxH/BxH, I _{SOURCE} = 500μA	0.8 x V _{DD}			V
		ISL706AxH/BxH/CxH, I _{SINK} = 1.2mA			0.3	V
		ISL70XAxH/CxH, V _{DD} = 1.2V, I _{SINK} = 100μA			0.3	V
		ISL70XBxH, V _{DD} = 1.2V, I _{SOURCE} = 4μA	0.9			V
Reset Output Leakage Current	I _{LEAK}	ISL705CxH, V _{OUT} = V _{DD}			1	μA
		ISL706CxH, V _{OUT} = V _{DD}			1	μA

ISL705AEH, ISL705BEH, ISL705CEH, ISL706AEH, ISL706BEH, ISL706CEH
ISL705ARH, ISL705BRH, ISL705CRH, ISL706ARH, ISL706BRH, ISL706CRH

Electrical Specifications Unless otherwise specified $V_{DD} = 4.75V$ to $5.5V$ for the ISL705AxH/BxH/CxH, $V_{DD} = 3.15V$ to $3.6V$ for the ISL706AxH/BxH/CxH, $T_A = -55^{\circ}C$ to $+125^{\circ}C$. **Boldface limits apply across the operating temperature range, $-55^{\circ}C$ to $+125^{\circ}C$; over a total ionizing dose of 100krad(Si) with exposure at a high dose rate of 50 - 300krad(Si)/s; and over a total ionizing dose of 50krad(Si) with exposure at a low dose rate of <10mrads(Si)/s. (Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS	MIN (Note 5)	TYP (Note 6)	MAX (Note 5)	UNIT
WATCHDOG SECTION						
Watchdog Time-Out Period	t _{WD}		1.00	1.60	2.25	s
Watchdog Input (WDI) Pulse Width	t _{WP}	ISL705AxH/BxH/CxH, V _{IL} = 0.4V, V _{IH} = 0.8 x V _{DD}	50			ns
		ISL706AxH/BxH/CxH, V _{IL} = 0.4V, V _{IH} = 0.8 x V _{DD}	100			ns
Watchdog Input (WDI) Threshold Voltage	V _{IL}	ISL705AxH/BxH/CxH			0.8	V
	V _{IH}	ISL705AxH/BxH/CxH	3.5			V
	V _{IL}	ISL706AxH/BxH/CxH			0.6	V
	V _{IH}	ISL706AxH/BxH/CxH	0.7 x V _{DD}			V
Watchdog Input (WDI) Current	I _{WDI}	ISL705AxH/BxH/CxH, WDI = V _{DD}			100	μA
		ISL705AxH/BxH/CxH, WDI = 0V	-100			μA
		ISL706AxH/BxH/CxH, WDI = V _{DD}			5	μA
		ISL706AxH/BxH/CxH, WDI = 0V	-5			μA
Watchdog Output ($\overline{WDO}$) Voltage	V _{WDO}	ISL705AxH/BxH/CxH, I _{SOURCE} = 800μA	V _{DD} - 1.5			V
		ISL705AxH/BxH/CxH, I _{SINK} = 1.2mA			0.4	V
		ISL706AxH/BxH/CxH, I _{SOURCE} = 500μA	0.8 x V _{DD}			V
		ISL706AxH/BxH/CxH, I _{SINK} = 500μA			0.3	V
MANUAL RESET SECTION						
Manual Reset ($\overline{MR}$) Pull-Up Current	I _{MR}	ISL705AxH/BxH/CxH, $\overline{MR}$ = 0V	-500		-100	μA
		ISL706AxH/BxH/CxH, $\overline{MR}$ = 0V	-250		-25	μA
Manual Reset ($\overline{MR}$) Pulse Width	t _{MR}	ISL705AxH/BxH/CxH	150			ns
		ISL706AxH/BxH/CxH	150			ns
Manual Reset ($\overline{MR}$) Input Threshold Voltage	V _{IL}	ISL705AxH/BxH/CxH			0.8	V
	V _{IH}		2.0			V
	V _{IL}	ISL706AxH/BxH/CxH			0.6	V
	V _{IH}		0.7 x V _{DD}			V
Manual Reset ($\overline{MR}$) to Reset Out Delay	t _{MD}	ISL705AxH/BxH/CxH			100	ns
		ISL706AxH/BxH/CxH			100	ns
THRESHOLD DETECTOR SECTION						
Power Fail Input (PFI) Input Threshold Voltage	V _{PFI}	ISL705AxH/BxH/CxH	1.20	1.25	1.30	V
		ISL706AxH/BxH/CxH	0.576	0.6	0.624	V
Power Fail Input (PFI) Input Current	I _{PFI}		-10		10	nA
Power Fail Output (PFO) Output Voltage	V _{PFO}	ISL705AxH/BxH/CxH, I _{SOURCE} = 800μA	V _{DD} - 1.5			V
		ISL705AxH/BxH/CxH, I _{SINK} = 3.2mA			0.4	V
		ISL706AxH/BxH/CxH, I _{SOURCE} = 500μA	0.8 x V _{DD}			V
		ISL706ARH/BRH/CRH, I _{SINK} = 1.2mA			0.3	V

Electrical Specifications Unless otherwise specified $V_{DD} = 4.75V$ to $5.5V$ for the ISL705AxH/BxH/CxH, $V_{DD} = 3.15V$ to $3.6V$ for the ISL706AxH/BxH/CxH, $T_A = -55^{\circ}C$ to $+125^{\circ}C$. **Boldface limits apply across the operating temperature range, $-55^{\circ}C$ to $+125^{\circ}C$; over a total ionizing dose of 100krad(Si) with exposure at a high dose rate of 50 - 300krad(Si)/s; and over a total ionizing dose of 50krad(Si) with exposure at a low dose rate of <10mrads(Si)/s. (Continued)**

PARAMETER	SYMBOL	TEST CONDITIONS	MIN (Note 5)	TYP (Note 6)	MAX (Note 5)	UNIT
PFI Rising Threshold Crossing to PFO Delay	t_{RPFI}	ISL705AxH/BxH/CxH		7	15	μs
		ISL706AxH/BxH/CxH		11	20	μs
PFI Falling Threshold Crossing to PFO Delay	t_{FPFI}	ISL705AxH/BxH/CxH		20	35	μs
		ISL706AxH/BxH/CxH		25	40	μs

NOTES:

5. Compliance to datasheet limits is assured by one or more methods: production test, characterization and/or design.
6. Typical values shown reflect $T_A = T_J = +25^{\circ}C$ operation and are not guaranteed.
7. Reset is the only parameter operable within 1.2V and the minimum recommended operating supply voltage.

Typical Performance Curves

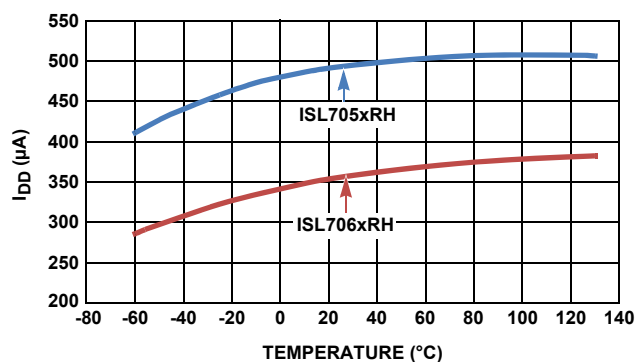


FIGURE 6. I_{DD} vs TEMPERATURE

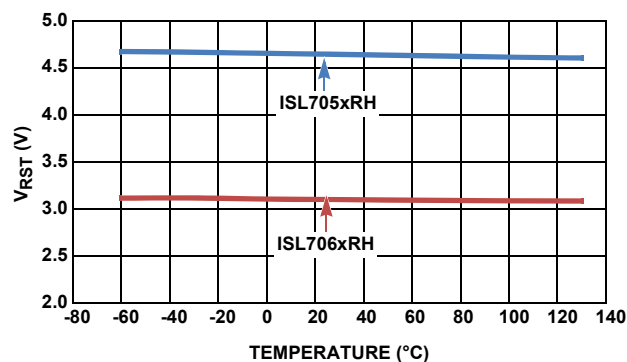


FIGURE 7. V_{RST} vs TEMPERATURE

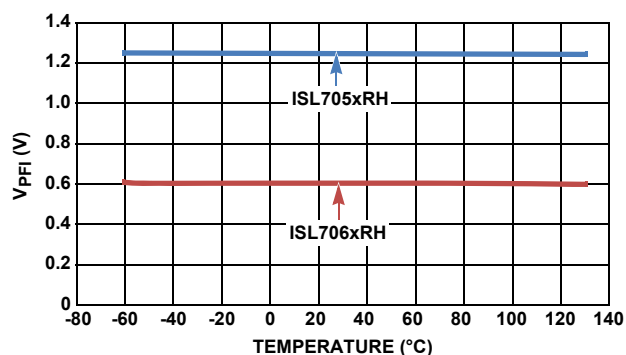


FIGURE 8. V_{PFI} vs TEMPERATURE

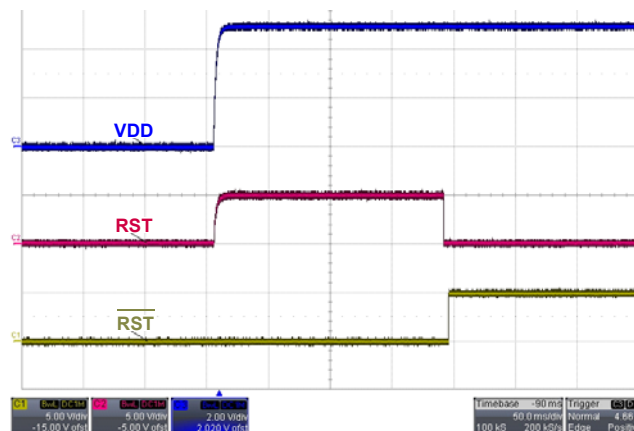


FIGURE 9. ISL705xRH RESET and $\overline{RST}$ ASSERTION

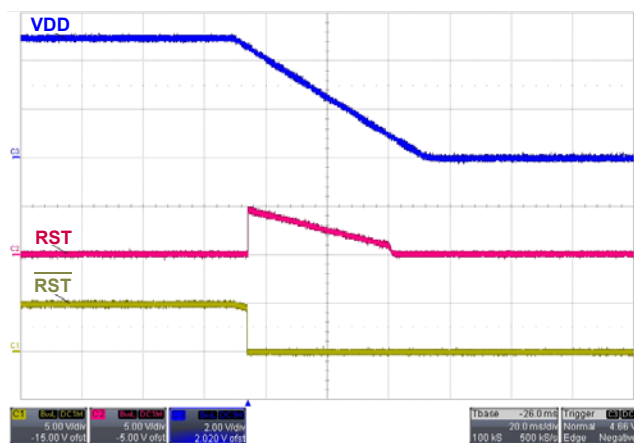


FIGURE 10. ISL705xRH RESET and $\overline{RST}$ DEASSERTION

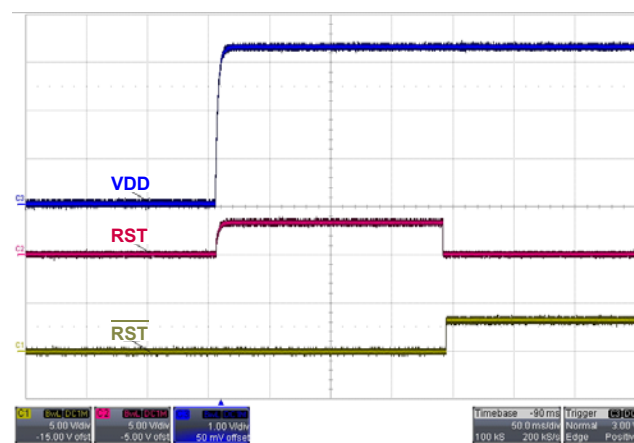


FIGURE 11. ISL706xRH RESET and $\overline{RST}$ ASSERTION

Typical Performance Curves (Continued)

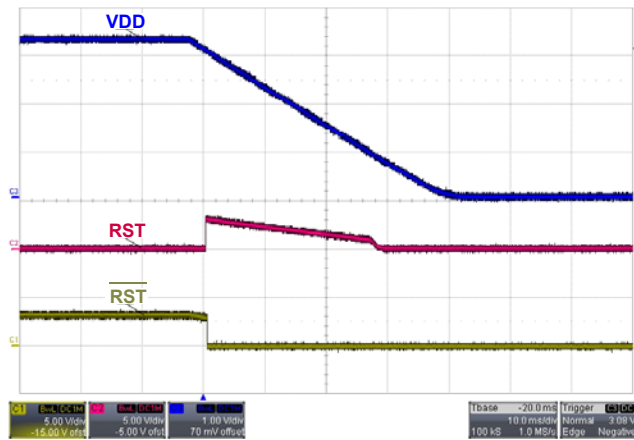


FIGURE 12. ISL706xRH RESET AND RESET DEASSERTION

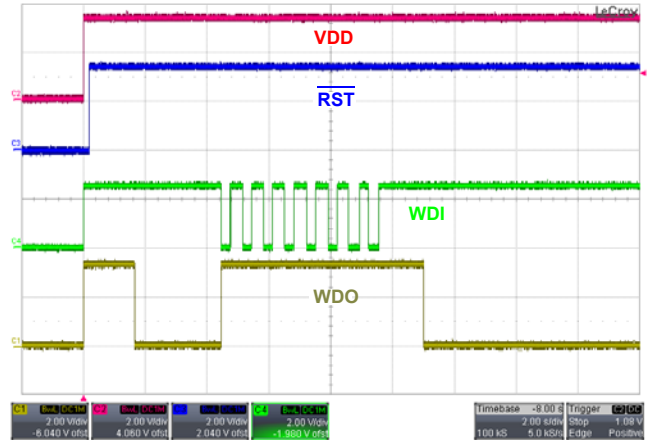


FIGURE 13. ISL706xEH START-UP TO RESET, WDO AND WDI FUNCTION

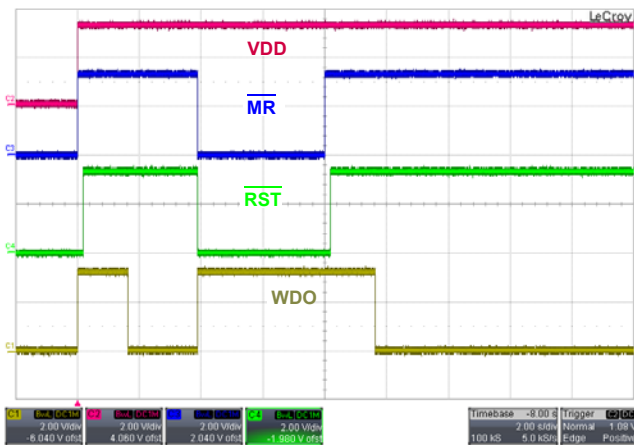


FIGURE 14. ISL706xEH START-UP TO RESET, MANUAL RESET AND WDO FUNCTION

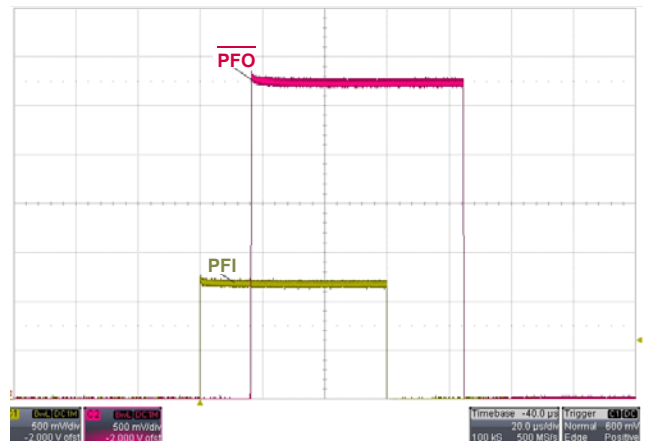


FIGURE 15. ISL705xRH PFI TO PFO RESPONSE

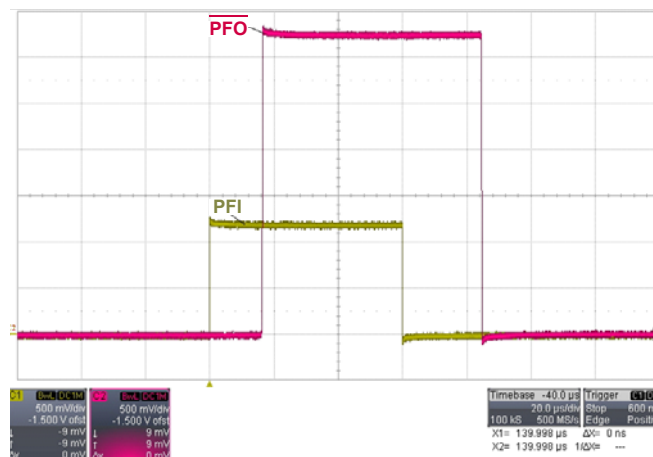


FIGURE 16. ISL706xRH PFI TO PFO RESPONSE

Post Radiation Characteristics Unless otherwise specified, $V_{DD} = 4.75V$ to $5.5V$ for the ISL705AEH/BEH/CEH only, $V_{DD} = 3.15V$ to $3.6V$ for the ISL706AEH/BEH/CEH, only $T_A = +25^\circ C$. This data is typical mean test data post radiation exposure at a rate of $<10\text{mrad(Si)}/s$. This data is intended to show typical parameter shifts due to low dose rate radiation. These are not limits nor are they guaranteed.

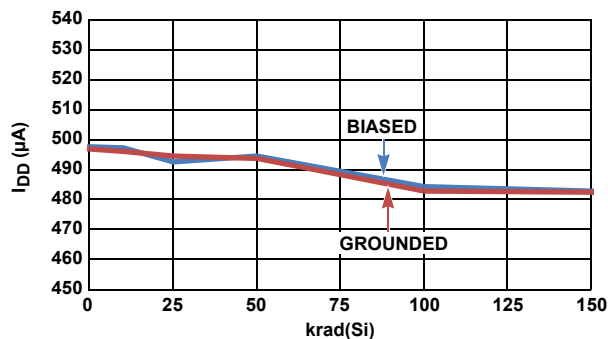


FIGURE 17. ISL705xEH I_{DD} vs LOW DOSE RATE RADIATION

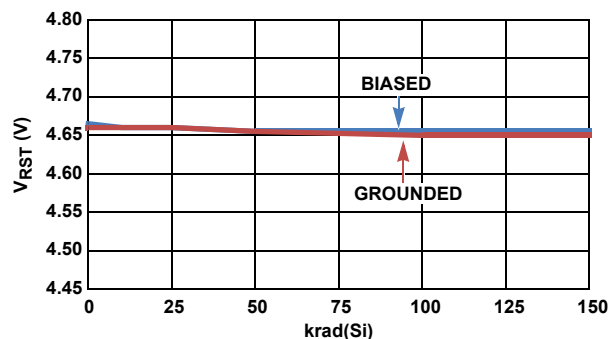


FIGURE 18. ISL705xEH V_{RST} vs LOW DOSE RATE RADIATION

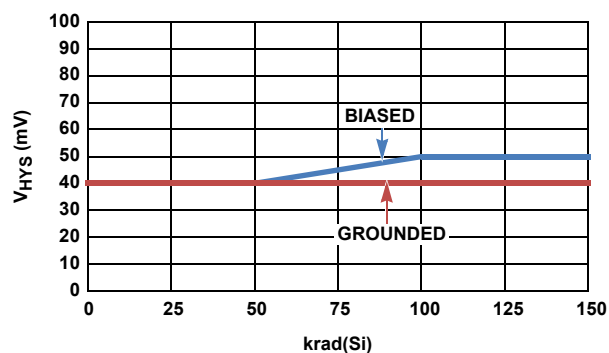


FIGURE 19. ISL705xEH V_{HYS} vs LOW DOSE RATE RADIATION

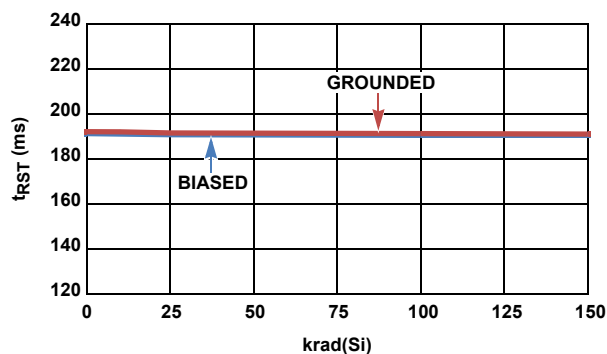


FIGURE 20. ISL705xEH t_{RST} vs LOW DOSE RATE RADIATION

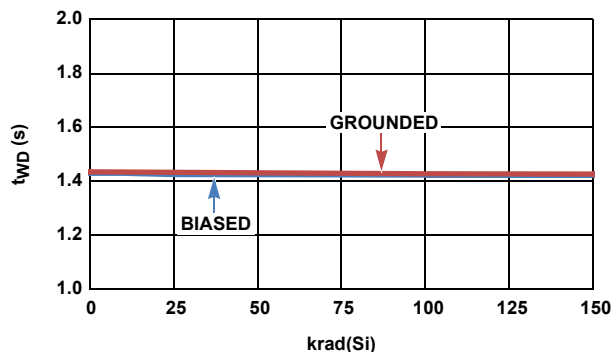


FIGURE 21. ISL705xEH t_{WD} vs LOW DOSE RATE RADIATION

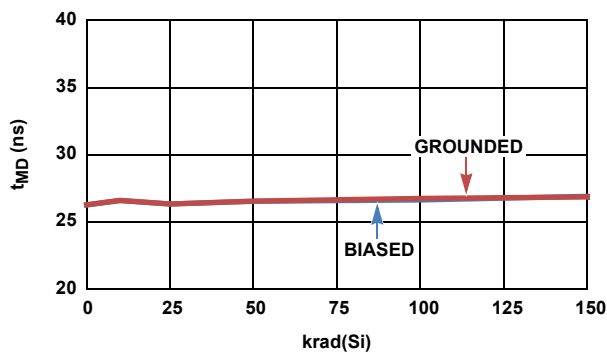


FIGURE 22. ISL705xEH t_{MD} vs LOW DOSE RATE RADIATION

Post Radiation Characteristics Unless otherwise specified, $V_{DD} = 4.75V$ to $5.5V$ for the ISL705AEH/BEH/CEH only, $V_{DD} = 3.15V$ to $3.6V$ for the ISL706AEH/BEH/CEH, only $T_A = +25^\circ C$. This data is typical mean test data post radiation exposure at a rate of $<10\text{mrad(Si)/s}$. This data is intended to show typical parameter shifts due to low dose rate radiation. These are not limits nor are they guaranteed. (Continued)

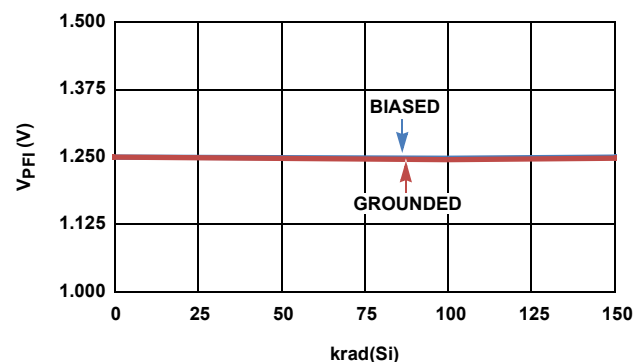


FIGURE 23. ISL705xEH V_{PFI} vs LOW DOSE RATE RADIATION

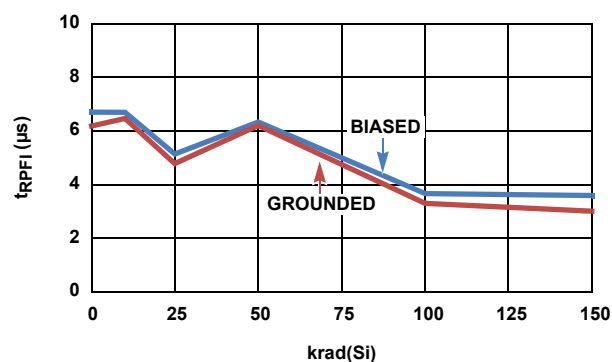


FIGURE 24. ISL705xEH t_{RPFI} vs LOW DOSE RATE RADIATION

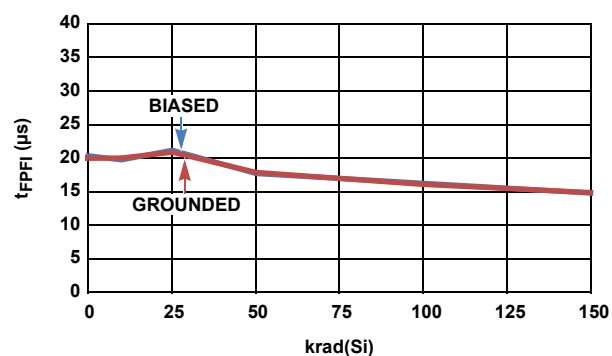


FIGURE 25. ISL705xEH t_{FPF1} vs LOW DOSE RATE RADIATION

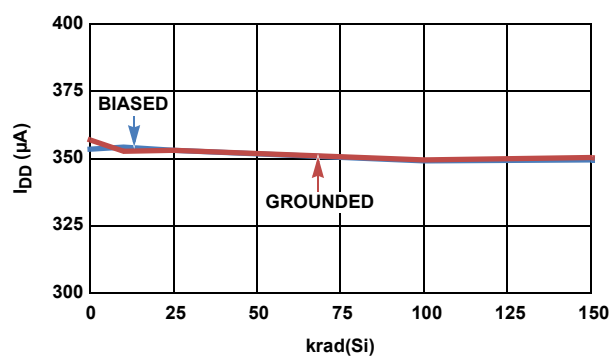


FIGURE 26. ISL706xEH I_{DD} vs LOW DOSE RATE RADIATION

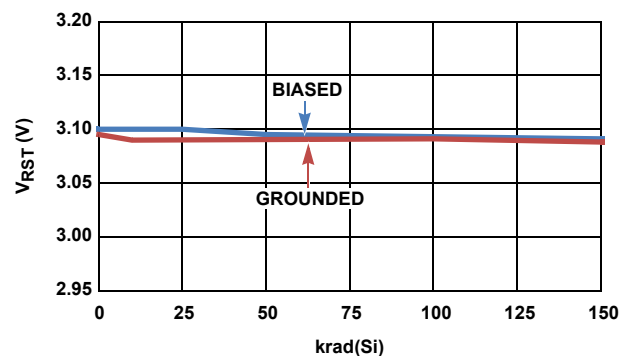


FIGURE 27. ISL706xEH V_{RST} vs LOW DOSE RATE RADIATION

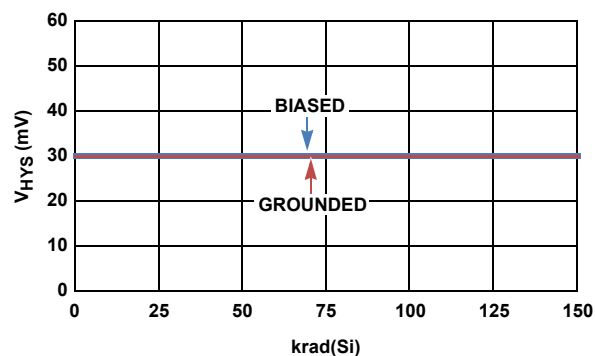


FIGURE 28. ISL706xEH V_{HYS} vs LOW DOSE RATE RADIATION

Post Radiation Characteristics Unless otherwise specified, $V_{DD} = 4.75V$ to $5.5V$ for the ISL705AEH/BEH/CEH only, $V_{DD} = 3.15V$ to $3.6V$ for the ISL706AEH/BEH/CEH, only $T_A = +25^\circ C$. This data is typical mean test data post radiation exposure at a rate of $<10\text{mrad(Si)}/s$. This data is intended to show typical parameter shifts due to low dose rate radiation. These are not limits nor are they guaranteed. (Continued)

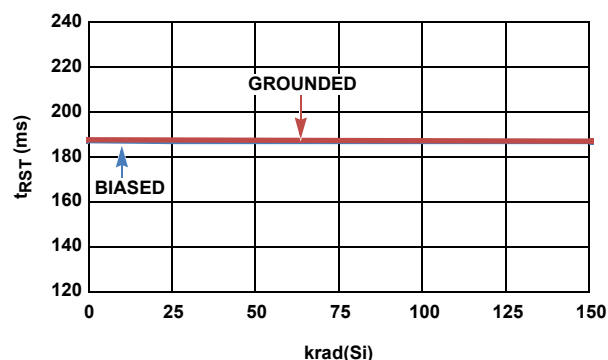


FIGURE 29. ISL706xEH t_{RST} vs LOW DOSE RATE RADIATION

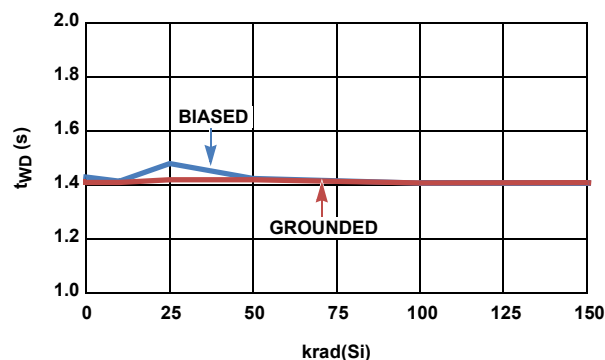


FIGURE 30. ISL706xEH t_{WD} vs LOW DOSE RATE RADIATION

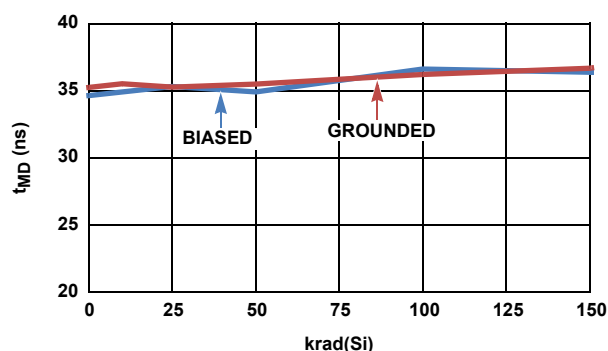


FIGURE 31. ISL706xEH t_{MD} vs LOW DOSE RATE RADIATION

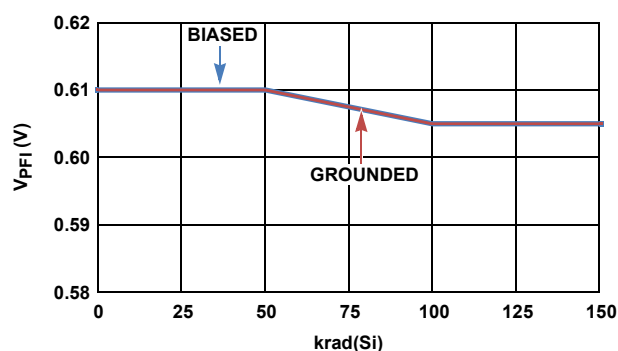


FIGURE 32. ISL706xEH V_{PFI} vs LOW DOSE RATE RADIATION

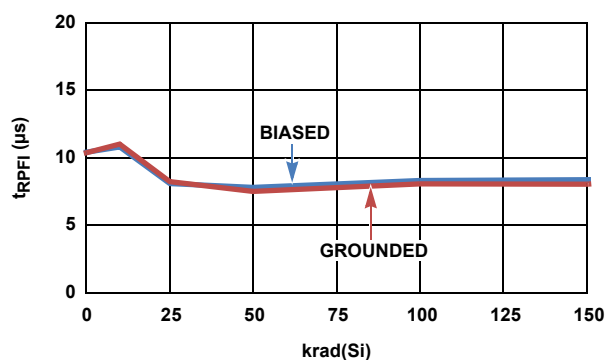


FIGURE 33. ISL706xEH t_{RPFI} vs LOW DOSE RATE RADIATION

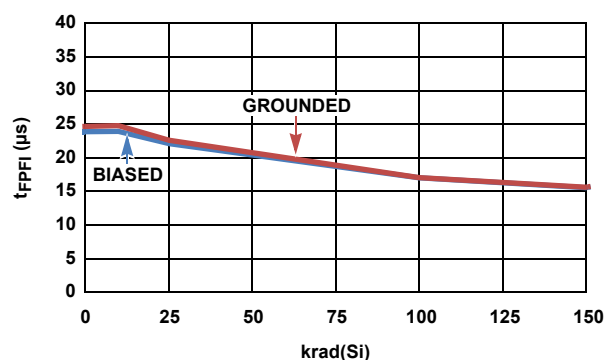


FIGURE 34. ISL706xEH t_{FPFI} vs LOW DOSE RATE RADIATION

Functional Overview

The ISL705xxH and ISL706xxH provide the functions needed for monitoring critical voltages in high reliability applications such as microprocessor systems. Functions of these supervisors include power-on reset control; supply voltage supervisions; power-fail detection; manual-reset assertion and a watchdog timer. The integration of all these functions along with their high threshold accuracy, low power consumption and radiation tolerance make these devices ideal for critical supply monitoring.

Reset Output

Reset control has long been a critical aspect of embedded control design. Microprocessors require a reset signal during power-up to ensure that the system environment is stable before initialization.

The reset signal provides several benefits:

- It prevents the system microprocessor from starting to operate with insufficient voltage.
- It prevents the processor from operating prior to stabilization of the oscillator.
- It ensures that the monitored device is held out of operation until internal registers are initialized.
- It allows time for an FPGA to perform its self configuration prior to initialization of the circuit.

On power-up, once V_{DD} reaches 1.2V, $\overline{RST}$ is guaranteed logic low. As V_{DD} rises, $\overline{RST}$ stays low. When V_{DD} rises above the reset threshold (V_{RST}), an internal timer releases $\overline{RST}$ after 200ms (typical). $\overline{RST}$ pulses low whenever V_{DD} degrades to below V_{RST} (see Figure 4). If a brownout condition occurs in the middle of a previously initiated reset pulse, the pulse is lengthened 200ms (typical).

On power-down, once V_{DD} falls below the reset threshold, $\overline{RST}$ stays low and is guaranteed to be low until V_{DD} drops below 1.2V.

The ISL705BxH and ISL706BxH active-high $\overline{RST}$ output is simply the complement of the $\overline{RST}$ output and is guaranteed to be valid with V_{DD} down to 1.2V. The ISL705CxH and ISL706CxH active-low open-drain reset output is functionally identical to $\overline{RST}$.

Power Failure Monitor

Besides monitoring V_{DD} for reset control, these devices have a Power Failure Monitor feature that supervises an additional critical voltage on the Power-Fail Input (PFI) pin. For example, the PFI pin could be used to provide an early power-fail warning, overvoltage detection or monitor a power supply other than V_{DD} . $\overline{PFO}$ goes low whenever PFI is less than V_{PFI} .

The threshold detector can be adjusted using an external resistor divider network to provide custom voltage monitoring for voltages greater than V_{PFI} , according to Equation 1 (see Figure 35).

$$V_{IN} = V_{PFI} \left(\frac{R_1 + R_2}{R_2} \right) \quad (\text{EQ. 1})$$

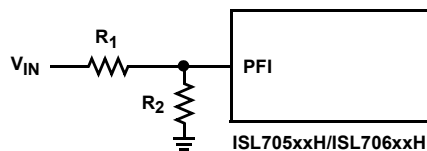


FIGURE 35. CUSTOM V_{TH} WITH RESISTOR DIVIDER ON PFI

Manual Reset

The manual reset input ($\overline{MR}$) allows designers to add manual system reset capability via a push button switch (see Figure 36). The $\overline{MR}$ input is an active low debounced input which asserts reset if the $\overline{MR}$ pin is pulled low to less than V_{IL} for at least 150ns. After $\overline{MR}$ is released, the reset output remains asserted for t_{RST} and then released. $\overline{MR}$ is a TTL/CMOS logic compatible, so it can be driven by external logic. By connecting $\overline{WDO}$ to $\overline{MR}$, one can force a watchdog time out to generate a reset pulse.

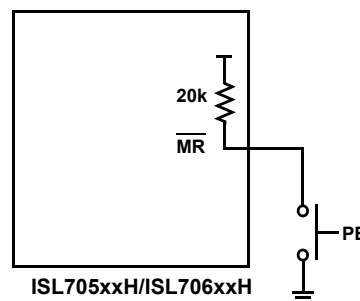


FIGURE 36. CONNECTING A MANUAL RESET PUSH-BUTTON

Watchdog Timer

The watchdog time circuit checks for coherent program execution by monitoring the $\overline{WDI}$ pin. If the processor does not toggle the watchdog input within t_{WDP} , $\overline{WDO}$ will go low. As long as reset is asserted or the $\overline{WDI}$ pin is tri-stated, the watchdog timer will stay cleared and not count. As soon as reset is released and $\overline{WDI}$ is driven high or low, the timer will start counting. Pulses as short as 50ns can be detected on the ISL705xxH, on ISL706xxH pulses as short as 100ns can be detected.

Whenever there is a low-voltage V_{DD} condition, $\overline{WDO}$ goes low. Unlike the reset outputs, however, $\overline{WDO}$ goes high as soon as V_{DD} rises above its voltage trip point (see Figure 5). With $\overline{WDI}$ open or connected to a tri-stated high impedance input, the watchdog timer is disabled and only pulls low when $V_{DD} < V_{RST}$.

Applications Information

Negative Voltage Sensing

This family of devices can be used to sense and monitor the presence of both a positive and negative rail. V_{DD} is used to monitor the positive supply while PFI monitors the negative rail. $\overline{PFO}$ is high when the negative rail degrades below a V_{TRIP} value and remains low when the negative rail is above the V_{TRIP} value. As the differential voltage across the R_1 , R_2 divider is increased, the resistor values must be chosen such that the PFI node is $< 1.25V$ when the $-V$ supply is satisfactory and the positive supply is at its maximum specified value. This allows the positive supply

to fluctuate within its acceptable range without signaling a reset when configured as shown in [Figure 37](#).

$$R_2 = \frac{R_1(V_{PFI} - V_{TRIP})}{V_{DD} - V_{PFI}} \quad (\text{EQ. 2})$$

In [Figure 37](#), the ISL705AxH is monitoring +5V through V_{DD} and -5V through PFI. In this example, the trip point (V_{TRIP}) for the negative supply rail is set for -4.5V. [Equation 2](#) can be used to select the appropriate resistor values. R_1 is selected arbitrarily as 100k Ω , $V_{DD} = 5V$, $V_{PFI} = 1.25V$ and $V_{TRIP} = (-4.5V)$. By plugging the values into [Equation 2](#) as shown in [Equation 3](#), it can be seen a resistor of 153.3k Ω is needed. The closest 1% resistor value is 154k Ω .

$$R_2 = \frac{100k(1.25 - (-4.5))}{5 - 1.25} = 153.3k\Omega \quad (\text{EQ. 3})$$

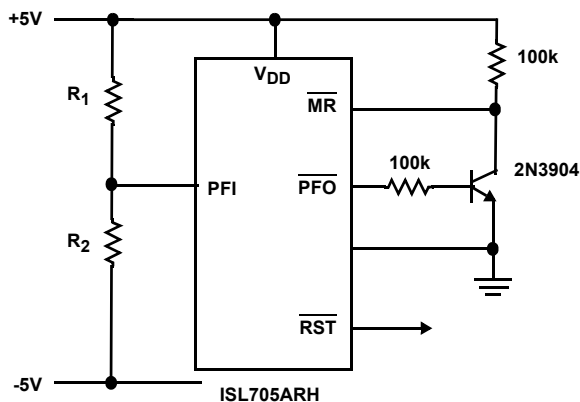


FIGURE 37. ±5V MONITORING

[Figure 5](#) also has a general purpose NPN transistor in which the base is connected to the $\overline{PFO}$ pin through a 100k Ω resistor. The emitter is tied to ground and the collector is tied to $\overline{MR}$ signal. This configuration allows the negative voltage sense circuit to initiate a reset if it is not within its regulation window. A pull-up on the $\overline{MR}$ ensures no false reset triggering when the negative voltage is within its regulation window.

Assuring a Valid $\overline{RST}$ Output

When V_{DD} falls below 1.2V, the $\overline{RST}$ output can no longer sink current and is essentially an open circuit. As a result, this pin can drift to undetermined voltages if left undriven. By adding a pull-down resistor to the $\overline{RST}$ pin as shown in [Figure 38](#), any stray charge or leakage currents will be drained to ground and keep $\overline{RST}$ low when V_{DD} falls below 1.2V. The resistor value (R_1) is not critical, however, it should be large enough not to load $\overline{RST}$ and small enough to pull $\overline{RST}$ to ground. A 100k Ω resistor would suffice, assuming there is no load on the $\overline{RST}$ pin during that time.

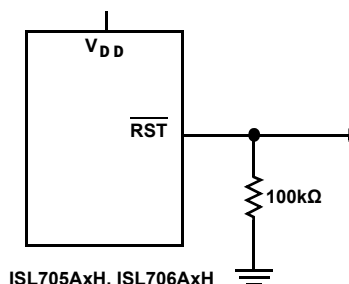
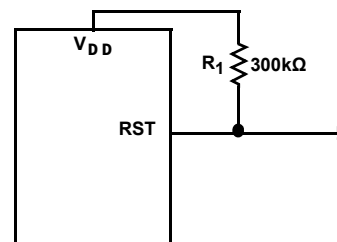


FIGURE 38. $\overline{RST}$ VALID TO GROUND CIRCUIT

Assuring a Valid $\overline{RST}$ Output

On the ISL705BxH and ISL706BxH, when V_{DD} falls below 1.2V, the $\overline{RST}$ output can no longer source enough current to track V_{DD} . As a result, this pin can drift to undetermined voltages if left undriven. By adding a pull-up resistor to the $\overline{RST}$ pin as shown in [Figure 39](#), $\overline{RST}$ will track V_{DD} below 1.2V. The resistor value (R_1) is not critical, however, it should be large enough not to exceed the sink capability of $\overline{RST}$ pin at 1.2V. A 300k Ω resistor would suffice, assuming there is no load on the $\overline{RST}$ pin during that time.

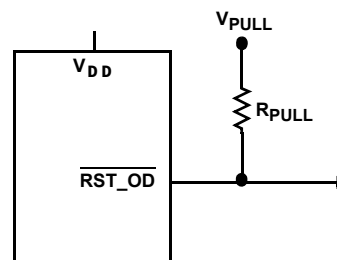


ISL705BxH, ISL706BxH

FIGURE 39. $\overline{RST}$ VALID TO GROUND CIRCUIT

Selecting Pull-up Resistor Values

The ISL705CxH and ISL706CxH have open drain active low reset outputs ($\overline{RST_OD}$). A pull-up resistor is needed to ensure $\overline{RST_OD}$ is high when V_{DD} is in a valid state ([Figure 40](#)). The resistor value must be chosen in order not to exceed the sink capability of the $\overline{RST_OD}$ pin. The ISL705AxH has a sink capability of 3.2mA and the ISL706CxH has a sink capability of 1.2mA. [Equation 4](#) may be used to select resistor R_{PULL} based on the pull-up voltage V_{PULL} . It is also important that the pull-up voltage does not exceed V_{DD} .



ISL706CxH, ISL705CxH

FIGURE 40. $\overline{RST_OD}$ PULL-UP CONNECTION

$$R_{PULL} = \frac{V_{PULL}}{I_{SINK}} \quad (\text{EQ. 4})$$

Adding Hysteresis to the PFI Comparator

The PFI comparator has no built-in hysteresis, however, the designer may add hysteresis by connecting a resistor from the $\overline{\text{PFO}}$ pin to the PFI pin, essentially adding positive feedback to the comparator (see [Figure 41](#)).

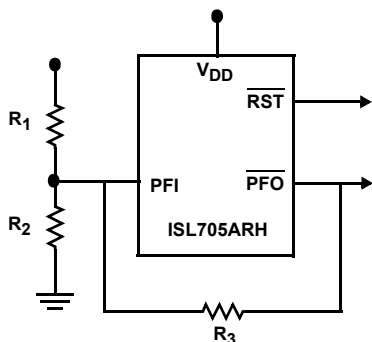


FIGURE 41. POSITIVE FEEDBACK FOR HYSTERESIS

The following procedure allows the system designer to calculate the components based on the requirements and on given data, such as supply rail voltages, hysteresis band voltage (V_{HB}) and reference voltage (V_{PFI}).

The comparator only has two states of operation. When it is low, the current through R_3 is $I_{R3} = V_{PFI}/R_3$. When the output is high, $I_{R3} = (V_{DD} - V_{PFI})/R_3$. The feedback current needs to be very small so it does not induce oscillations; 200nA is a good starting point. Now two values of R_3 can be calculated with $V_{DD} = 5V$ and $V_{PFI} = 1.25V$; $R_3 = 6.25M\Omega$ or $11.25M\Omega$, select the lowest value of the two.

With R_3 selected as $6.2M\Omega$ (closest standard 1% resistor), R_1 can be calculated as:

$$R_1 = R_3 \left(\frac{V_{HB}}{V_{DD}} \right) = 124k\Omega \quad (\text{EQ. 5})$$

With V_{HB} selected at 100mV. The closest standard value for R_1 is $124k\Omega$. Then next step is select the rising trip voltage (V_{TR}) such that:

$$V_{TR} > V_{PFI} \left(1 + \frac{V_{HB}}{V_{DD}} \right) \quad (\text{EQ. 6})$$

The rising threshold voltage is selected at 3.0V and R_2 is calculated by [Equation 7](#).

$$R_2 = 1 / \left[\left(\frac{V_{TR}}{(V_{PFI} \times R_1)} \right) - \left(\frac{1}{R_1} \right) - \left(\frac{1}{R_3} \right) \right] \quad (\text{EQ. 7})$$

Plugging in all the variables in [Equation 7](#) and solving for R_2 yields $90.9k\Omega$. Note that the $90.9k\Omega$ solution includes rounding to the closest standard 1% resistor value. The final step is to verify the trip voltages.

$$V_{TR} = (V_{PFI}) \times R_1 \left[\left(\frac{1}{R_1} \right) + \left(\frac{1}{R_2} \right) + \left(\frac{1}{R_3} \right) \right] \quad (\text{EQ. 8})$$

$$V_{TF} = V_{TR} - \left(\frac{R_1 \times V_{DD}}{R_3} \right) \quad (\text{EQ. 9})$$

The rising voltage, V_{TR} , is calculated as 2.98V and the falling voltage, V_{TF} , is calculated as 2.88V, so 100mV hysteresis is achieved.

An additional item to consider is that the output voltage is equal to V_{DD} , however, according to the ["Electrical Specifications"](#) on [page 7](#), the output of the PFI comparator is guaranteed to be at least $(V_{DD}-1.5)$ volts. When you take this worst case into account, the hysteresis can be as low at 70mV.

Special Application Considerations

Using good decoupling practices will prevent transients (i.e., due to switching noises and short duration droops in the supply voltage) from causing unwanted resets and reduce the power-fail circuit's sensitivity to high-frequency noise on the line being monitored.

When the WDI input is left unconnected, it is recommended to place a $10\mu F$ capacitor to ground to reduce single event transients from arising in the $\overline{\text{WDO}}$ pin.

As described in the ["Electrical Specifications"](#) table on [page 8](#), there is a delay on the $\overline{\text{PFO}}$ pin whenever PFI crosses the threshold. This delay is due to internal filters on the PFI comparator circuitry which were added to mitigate single event transients. If the PFI input transitions below or above the threshold and the duration of the transition is less than the delay, the PFO pin will not change states.

Package Characteristics

Weight of Packaged Device

0.31 Grams typical

Lid Characteristics

Finish: Gold

Lid Potential: Unbiased

Case Isolation to Any Lead: $20 \times 10^9 \Omega$ (minimum)

BACKSIDE FINISH

Silicon

PROCESS

0.6 μ m BiCMOS Junction Isolated

ASSEMBLY RELATED INFORMATION

Substrate Potential

Unbiased

Die Characteristics

Die Dimensions

2030 μ m x 2030 μ m (79.9 mils x 79.9 mils)

Thickness: 483 μ m $\pm$ 25.4 μ m (19.0 mils $\pm$ 1 mil)

ADDITIONAL INFORMATION

Worst Case Current Density

$< 2 \times 10^5 \text{ A/cm}^2$

Interface Materials

GLASSIVATION

Type: Silicon Oxide and Silicon Nitride

Thickness: 0.3 μ m $\pm$ 0.03 μ m to 1.2 μ m $\pm$ 0.12 μ m

TOP METALLIZATION

Type: AlCu (99.5%/0.5%)

Thickness: 2.7 μ m $\pm$ 0.4 μ m

Transistor Count

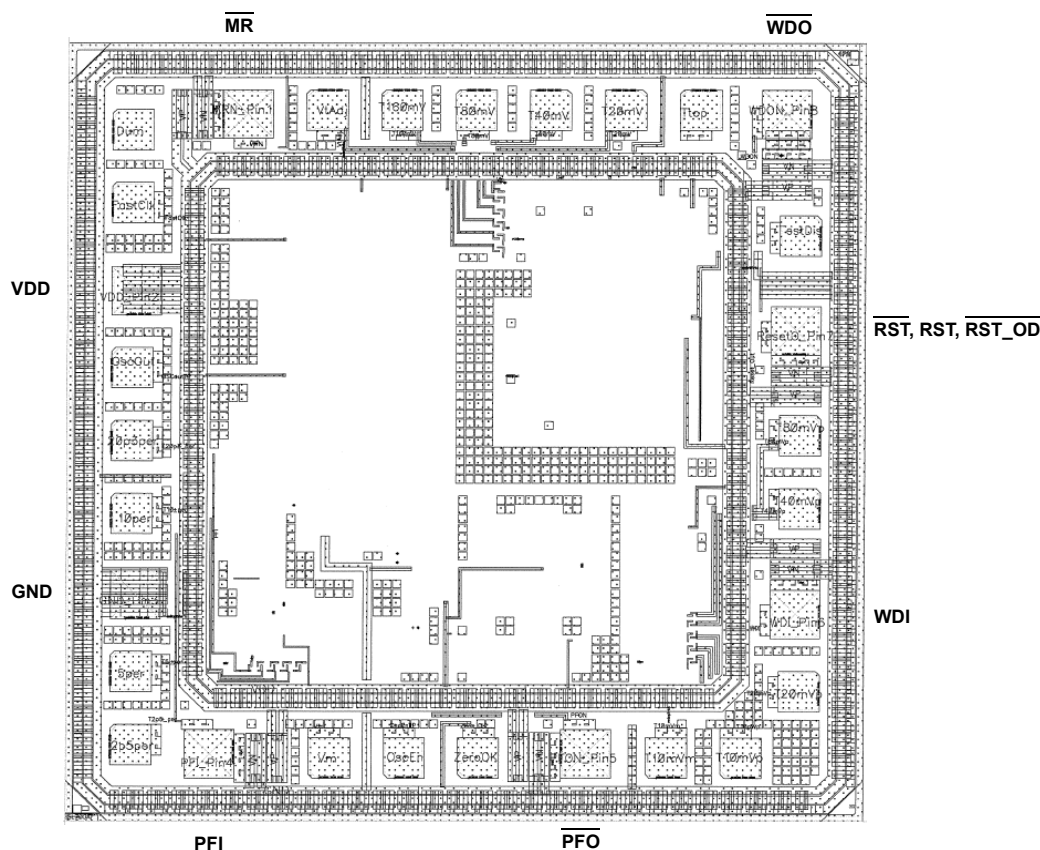
1400

Layout Characteristics

Step and Repeat

2030 μ m x 2030 μ m

Metallization Mask Layout



ISL705AEH, ISL705BEH, ISL705CEH, ISL706AEH, ISL706BEH, ISL706CEH
ISL705ARH, ISL705BRH, ISL705CRH, ISL706ARH, ISL706BRH, ISL706CRH

TABLE 1. DIE LAYOUT X-Y COORDINATES

PAD NAME	PAD NUMBER	X (μm)	Y (μm)	dX (μm)	dY (μm)	BOND WIRES PER PAD
$\overline{\text{MR}}$	1	0	0	110	110	1
V_{DD}	2	-266.1	-435.35	110	110	1
GND	3	-266.1	-1184.75	110	110	1
PFI	4	-86.1	-1578	110	110	1
$\overline{\text{PFO}}$	5	818.85	-1578	110	110	1
WDI	6	1321.9	-1233.5	110	110	1
$\overline{\text{RST}}, \text{RST}, \text{RST_OD}$	7	1321.9	-534.05	110	110	1
$\overline{\text{WDO}}$	8	1297	0	110	110	1

NOTE:

8. Origin of coordinates is the centroid of pad 1.

Revision History

The revision history provided is for informational purposes only and is believed to be accurate, but not warranted. Please go to web to make sure you have the latest Rev.

DATE	REVISION	CHANGE
July 29, 2016	FN7662.4	Added ISL705xEH and ISL706xEH product information throughout datasheet. Updated Figure 4 on page 5. Added Figures 13 and 14. Removed Post Radiation Characteristics table. Updated "Watchdog Timer" on page 14 by removing (1.0s min) reference. Updated "Interface Materials" on page 17 by removing second "Top Metallization" section.
February 10, 2015	FN7662.3	Added part number ISL706CRH to the header of pages 2 through 12, (It had been mistakenly covered up).
December 9, 2014	FN7662.2	Added SEE, ELDRS and SPICE Model reports to Related Literature on page 1. page 2 added to Ordering Information table: "Specifications for Rad Hard QML devices are controlled by the Defense Logistics Agency Land and Maritime (DLA). The SMD numbers listed in the "Ordering Information" table on page 2 must be used when ordering." Updated POD on page 20 to most recent revision with following changes: a) Package t _{kn} , Changed From: 0.115/0.070 (2.92/1.18) To: 0.110/0.087 (2.79/2.21) b) Bottom of lead to bottom of package, Changed From: 0.045/0.026" (1.14/0.66) To: 0.036/0.026 (0.92/0.66) c) Lead length, Changed: From: 0.370/0.250 (9.40/6.35) To: 0.370/0.325 (9.40/8.26) d) Lead t _{kn} : On the side view there was a typo on lead t _{kn} , corrected: From: 0.09/0.04 (0.23/0.10) To: 0.009/0.004 (0.23/0.10) Modified Note 2 by adding the words "...in addition to or instead of"...
November 1, 2011	FN7662.1	Page 13: Updated the transistor count to 1400 from 25000. Pages 7, 9: Removed erroneous overline bars in Figures 8-11.
September 15, 2011	FN7662.0	Initial release

About Intersil

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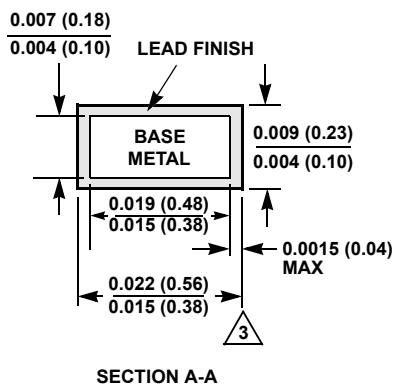
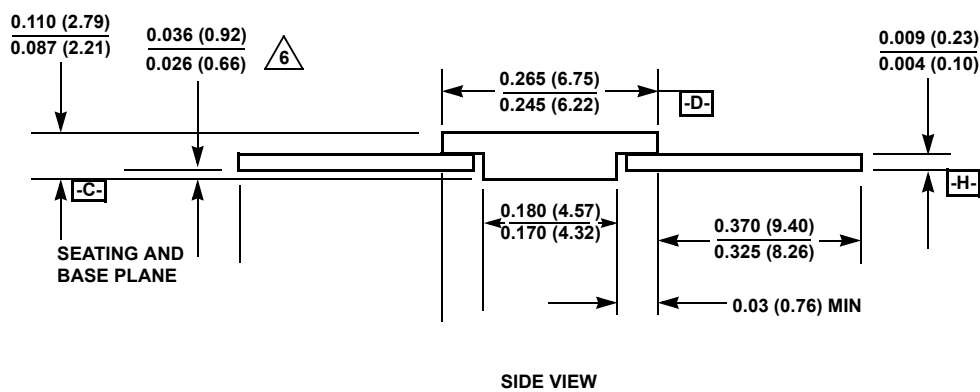
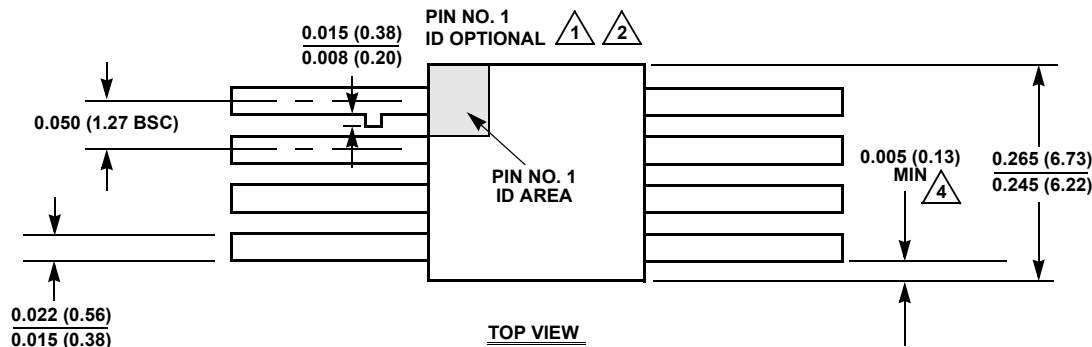
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Package Outline Drawing

K8.A

8 LEAD CERAMIC METAL SEAL FLATPACK PACKAGE

Rev 4, 12/14



NOTES:

1. Index area: A notch or a pin one identification mark shall be located adjacent to pin one and shall be located within the shaded area shown. The manufacturer's identification shall not be used as a pin one identification mark. Alternately, a tab may be used to identify pin one.
2. If a pin one identification mark is used in addition to or instead of a tab, the limits of the tab dimension do not apply.
3. The maximum limits of lead dimensions (section A-A) shall be measured at the centroid of the finished lead surfaces, when solder dip or tin plate lead finish is applied.
4. Measure dimension at all four corners.
5. For bottom-brazed lead packages, no organic or polymeric materials shall be molded to the bottom of the package to cover the leads.
6. Dimension shall be measured at the point of exit (beyond the meniscus) of the lead from the body. Dimension minimum shall be reduced by 0.0015 inch (0.038mm) maximum when solder dip lead finish is applied.
7. Dimensioning and tolerancing per ANSI Y14.5M - 1982.
8. Controlling dimension: INCH.